

# STV250N55F3

### N-channel 55 V, 1.5 mΩ, 250 A, PowerSO-10 STripFET™ Power MOSFET

### Features

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub> max	ID
STV250N55F3	55 V	< 2.2 mΩ	250 A

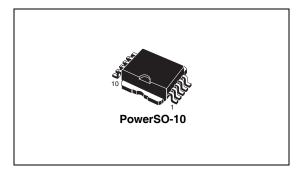
- Conduction losses reduced
- Low profile, very low parasitic inductance

### Application

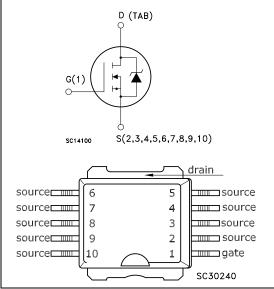
Switching applications

### Description

This n-channel enhancement mode Power MOSFET is the latest refinement of STMicroelectronics unique "single feature size" strip-based process with less critical alignment steps and therefore a remarkable manufacturing reproducibility. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and low gate charge.



# Figure 1. Internal schematic diagram and connection diagram (top view)



#### Table 1. Device summary

Order code	Marking	Package	Packaging
STV250N55F3	250N55F3	PowerSO-10	Tape and reel

March	2009
march	2000

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# 1 Electrical ratings

Table 2.	Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	55	V
V <sub>GS</sub>	Gate-source voltage	± 20	V
Ι <sub>D</sub>	Drain current (continuous) at $T_C = 25 \text{ °C}$	250	А
Ι <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C	175	А
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	1000	А
P <sub>TOT</sub> <sup>(2)</sup>	Total dissipation at $T_{C} = 25 \ ^{\circ}C$	300	W
	Derating factor	2.0	W/°C
E <sub>AS</sub> <sup>(3)</sup>	Single pulse avalanche energy	1	J
T <sub>stg</sub>	Storage temperature		°C
Тj	Operating junction temperature	55 to 175	°C

1. Pulse width limited by safe operating area

2. This value is rated according to Rthj-c

3. Starting Tj = 25 °C,  $I_D$  = 60 A,  $V_{DD}$  = 35 V

#### Table 3. Thermal data

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case max.	0.5	°C/W
Rthj-pcb <sup>(1)</sup>	Thermal resistance junction-pcb max.	50	°C/W

1. When mounted on 1 inch<sup>2</sup> FR-4 2 oz Cu



## 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	55			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max rating, V <sub>DS</sub> = Max rating, T <sub>c</sub> = 125 °C			1 10	μΑ μΑ
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0)	V <sub>DS</sub> = ± 20 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	2		4	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 75 A		1.5	2.2	mΩ

Table 4.	On /off states
	On Jon States

#### Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V}, \text{ f} = 1 \text{ MHz}, \text{ V}_{GS} = 0$		6800 1450 15		pF pF pF
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 44 \text{ V}, I_D = 120 \text{ A},$ $V_{GS} = 10 \text{ V}$ Figure 14		100 30 26		nC nC nC

	owneeling times					
Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on delay time Rise time	$V_{DD} = 27.5 \text{ V}, I_{D} = 60 \text{ A}$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V},$ <i>Figure 13</i>		25 150		ns ns
t <sub>d(off)</sub> t <sub>f</sub>	Turn-off delay time Fall time	$V_{DD} = 27.5 \text{ V}, I_D = 60 \text{ A} \\ R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}, \\ Figure 13$		110 50		ns ns

Table 6. Switching times

#### Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current				250	Α
I <sub>SD</sub> <sup>(1)</sup>	Source-drain current (pulsed)				1000	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	$I_{SD} = 120 \text{ A}, V_{GS} = 0$			1.5	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 120 A, di/dt = 100 A/μs		60		ns
Q <sub>rr</sub>	Reverse recovery charge	V <sub>DD</sub> = 35 V, T <sub>j</sub> = 150 °C		110		nC
I <sub>RRM</sub>	Reverse recovery current	Figure 18		3.5		А

1. Pulse width limited by safe operating area

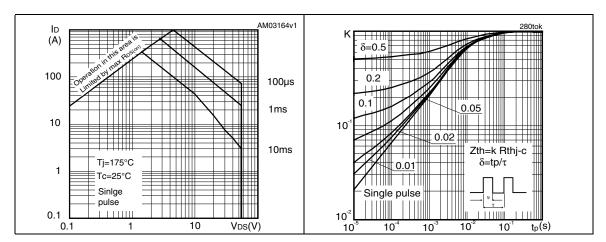
2. Pulsed: Pulse duration =  $300 \ \mu$ s, duty cycle 1.5%



### 2.1 Electrical characteristics (curves)

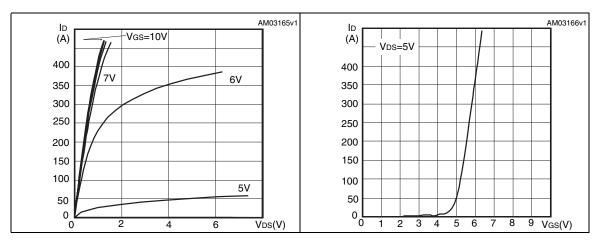


Figure 3. Thermal impedance



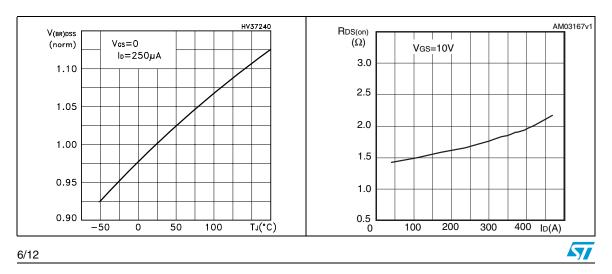






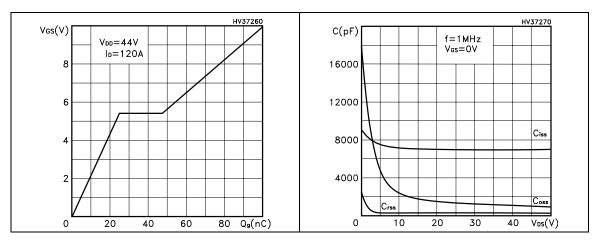






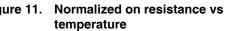
<u>нv37290\_</u>ь

150 Ū(℃)



#### Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

Figure 10. Normalized gate threshold voltage Figure 11. vs temperature



Vcs=10V Id=75A

-50

0

100

50

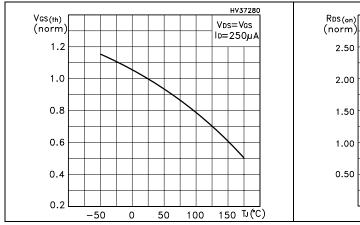
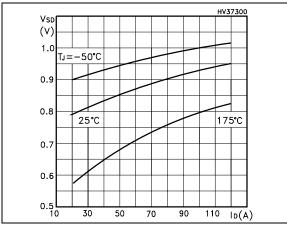


Figure 12. Source-drain diode forward characteristics



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### 3 Test circuits

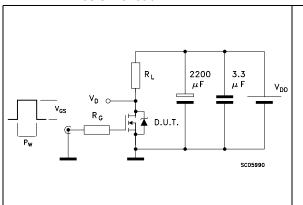


Figure 13. Switching times test circuit for resistive load

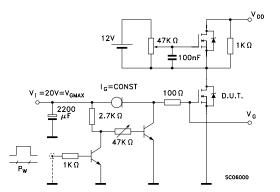
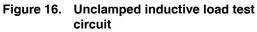
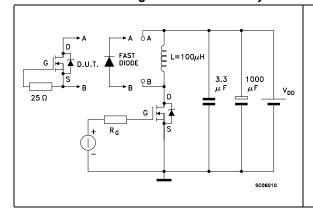


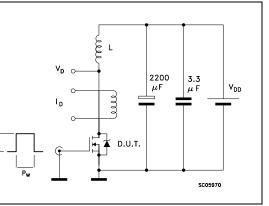
Figure 14. Gate charge test circuit

Figure 15. Test circuit for inductive load Figure switching and diode recovery times

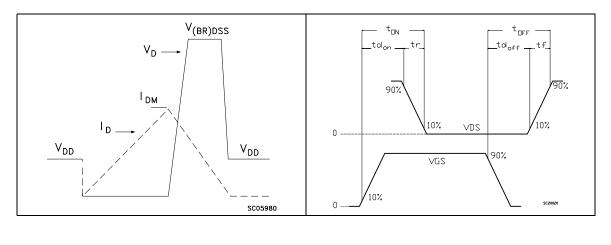












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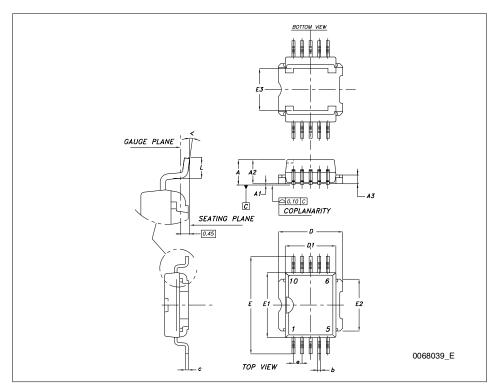
### 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



Dim	mm		
	Min	Тур	Мах
Α			3.70
A1	0.00		0.10
A2	3.40		3.60
A3	1.25		1.35
b	0.40		0.53
С	0.35		0.55
D	9.40		9.60
D1	7.40		7.60
E	13.80		14.40
E1	9.30		9.50
E2	7.20		7.60
E3	5.90		6.10
е		1.27	
L	0.95		1.65
<	0 <sup>0</sup>		8 <sup>0</sup>





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# 5 Revision history

#### Table 8. Document revision history

Date	Revision	Changes
25-Oct-2007	1	Initial release
20-Mar-2008	2	Content reworked to improve readability, no technical changes.
10-Nov-2008	3	Document status promoted from preliminary data to datasheet.
02-Mar-2009	4	Figure 2 has been updated.



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